Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/643,404	TANAKA ET AL.	
Examiner	Art Unit	

1614

Brian S. Kwon

SEARCHED					
Class	Subclass	Date	Examiner		
updated	see search notes	7/26/2007	вк		
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			4		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
514	404	7/26/2007	ВК		
	406				
	443				
514/469,471,412,427					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Updated (STN, EAST, NPL)	7/26/2007	вк	
Updated (Continuity data, inventor name search)			
	Y		